Search Notes			

Application/Control No.	Ap _l Rec
10/006,044	SIF
Examiner	Art

Applicant(s)/Patent under Reexamination	
SIH ET AL.	
Art Unit	
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Hau	Н.	Nguyen

SEARCHED			
Class	Subclass	Date	Examiner
345	572,537, 547, 562, 574	3/29/2007	НИ
348	154,700,7	3/29/2007	HN
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
345	572, 574,	3/29/2007	HN	
	537			
see attached				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Search Notes (updated) 345/572, 574, 537, 562, 547 348/154, 700, 716	3/29/2007	HN	